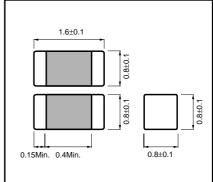
Multi-layer ceramic chip capacitors

MCH18 (1608 (0603) size, chip capacitor)

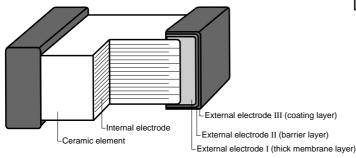
●Features

- 1) Small size (1.6 x 0.8 x 0.8 mm) makes it perfect for lightweight portable devices.
- Comes packed either in tape to enable automatic mounting or in bulk cases.
- Precise uniformity of shape and dimentions highly efficient automatic mounting.
- 4) Barrier layer and end terminations to improve solderability.

●External dimensions (Units : mm)



Structure



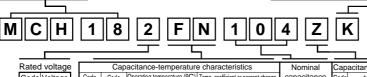
Product designation

Part No.

Code	Product thickness	Packaging specifications	Reel	Basic ordering (pcs.)
K	0.8mm	Paper tape (width 8 mm, pitch 4 mm)	φ180mm (7in.)	4,000
L	0.8mm	Paper tape (width 8 mm, pitch 4 mm)	φ330mm (13in.)	16,000
С	0.8mm	Bulk case	_	15,000

Ree I(\(\phi\)180,\(\phi\)330mm): compatible with EIAJ ET-7200A Bulk case: compatible with EIAJ ET-7201A

Packaging style



Rated voltage	Rated voltage Capacitance-temperature characteristics			e characteristics	Nominal	Сар	acitance tolerance
Code Voltage	Code	Code	Operating temperature (°C)	Temp. coefficient or percent change	capacitance	Code	tolerance
2 25V	Α	CG(C0G)	-55~+125	±30ppm/°C		C	±0.25pF (0.5 ~ 5pF)
3 16V	CN	R	-55~+125	±15%		D	±0.5pF (5.1 ~ 10pF)
5 50V]	В	-25~+85	±10%	3-digit designation	J	±5% (11pF or more)
		(X7R)	(-55~+125)	(±15%)	according to IEC	ĸ	±10%
	FN	F	-25~+85	+30%,-80%		L^	±10%
		(Y5V)	(-30~+85)	(+22%,-82%)		z	+80%, -20%

^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.



●Capacitance range

For thermal compensation

Part number. MCH18					
. arriva					
Capacitance(pF)	Temperature characteristics Rated voltage	A (CG) (C0G)			
	Tolerance (V)	50			
0.5					
0.75 1					
1.1		×××××			
1.2					
1.3					
1.5 1.6					
1.8					
2		*****			
2.2 2.4	C (± 0.25pF)				
2.7					
3					
3.3					
3.6 3.9					
4					
4.3 4.7					
4. <i>7</i> 5					
5.1		××××			
5.6	D (± 0.5pF)				
6.2		×××××			
6.8					
7					
7.5 8					
8.2		****			
9		×××××			
9.1 10					
11		****			
12 13		×××××			
15					
16					
18					
20 22					
24					
27		×××××			
30 33					
36	J (±5%)				
39 43					
43 47					
51					
56					
62 68					
75					
82		×××××			
91 100					
-	l .				

Part nur	MCH18	
	Temperature characteristics	A (CG) (C0G)
Capacitance (pF)	Rated voltage Tolerance (V)	50
110		
120		
130		
150		
160		
180		
200		
220		******
240		
270		*****
300	J (± 5%)	
330		
360		
390		
430		
470		
510		<u> </u>
560		
620		*****
680		
750		
820		*****
910		
1,000		

Product thickness (mm) 0.8 ± 0.1

^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

High dielectric constant

Part num	MCH18					
Capacitance(pF)	Temperature characteristics	CN (R) (B) (X7R)	FN (F) (Y5V)		′)
Capacitarios(p.)	Rated voltage (V)	50	25	50	25	16
	Tolerance	K (±	10%)	Z	(+80%, –20	%)
220		*****				
270 330		****				
390		NO.				
470 560						
680						
820						
1,000		******		******		
1,200						
1,500						
1,800		IXXXXXXI		IXXXXXXI		
2,200 2,700						
3,300		******				
3,900						
4,700						
5,600						
6,800						
8,200 10,000 (0.01μF)		*****				
12,000						
15,000		××××				
18,000						
22,000		*****		*****		
27,000			NXXXXXI			
33,000						
39,000 47,000			*****	*****		
56,000			XXXXXX	MXXXXXII		
68,000			*****			
82,000						
100,000 (0.1μF)						
120,000 150,000						
180,000						
220,000						
270,000						******
330,000						
390,000						
470,000						
560,000						
680,000 1,000,000 (1μF)						
1,200,000						
1,500,000						
1,800,000						
2,200,000						

Product thickness (mm) 0.8 ± 0.1

^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

Characteristics

Class 1 (For thermal compensation)

	Temperature characteristics	A (CG) (C0G)	Test methods / conditions		
Item		A (CG) (COG)	(based on JIS C 5102)		
Operating temperature		−55°C ~ +125°C			
Nominal capacitance (C)		Must be within the specified tolerance range.	Based on paragraph 7.8 and paragraph 9 Measured at room temperature and standard humidity 1000pF or less Measurement frequency: 1± 0.1MHz		
Dissipation factor $(\tan \delta)$		100 / (400 + 20C)% or less (Less than 30 pF) 0.1% or less (30 pF or larger)	Measurement voltage : 1± 0.1Vrm Over 1000pF Measurement frequency : 1± 0.1kHz Measurement voltage : 1± 0.1Vrm		
Insulation resist	tance (IR)	10,000MΩ or $500 M\Omega \cdot \mu F$, whichever is smaller	Based on paragraph 7.6 Measurement is made after rated voltage is applied for 60 ± 5s.		
Withstanding vo	oltage	The insulation must not be damaged.	Based on paragraph 7.1 Apply 300% of the rated voltage for 1 to 5s then measure.		
Temperature ch	naracteristics	Within 0 \pm 30ppm / $^{\circ}\text{C}$	The temperature coefficients in table 12, paragraph 7.12 are calculated at 20°C and high temperature.		
Terminal adherence		No detachment or signs of detachment.	Based on paragraph 8.11.2 Apply 5N for 10 ± 1s in the direction indicated by the arrow. Pressure (5N) Test board Capacitor		
	Appearance	There must be no mechanical damage.	Chip is mounted to a board in the		
Resistance to vibration	Rate of capacitance change	Must be within initial tolerance.	manner shown on the right, subjected to vibration (type A in paragraph 8.2),		
	Dissipation factor (tanδ)	Must satisfy initial specified value.	and measured 24 ± 2 hrs. later. Board		
Solderability		At least 3 / 4 of the surface of the two terminals must be covered with new solder.	Based on paragraph 8.13 Soldering temperature: 235 ± 5°C Soldering time: 2 ± 0.5s		
	Appearance	There must be no mechanical damage.			
	Rate of capacitance change	\pm 2.5% or \pm 0.25 pF , whichever is larger.	Based on paragraph 8.14		
Resistance to soldering	Dissipation factor (tanδ)	Must satisfy initial specified value.	Soldering temperature : 260 ± 5°C Soldering time : 5 ± 0.5s		
heat	Insulation resistance	$10,\!000M\Omega$ or $500M\Omega\cdot\!\mu F$, whichever is smaller	Preheating : 150 ± 10°C for 1 to 2 min.		
	Withstanding voltage	The insulation must not be damaged.	16211111		
	Appearance	There must be no mechanical damage.			
Temperature	Rate of capacitance change	$\pm~2.5\%\pm0.25~\text{pF}$, whichever is larger.	Based on paragraph 9.3		
cycling	Dissipation factor (tanδ)	Must satisfy initial specified value.	Number of cycles : 5 Capacitance measured after 24 ± 2 hrs.		
	Insulation resistance	10,000M Ω or 500M Ω ·μF , whichever is smaller			
Humidity load test	Appearance	There must be no mechanical damage.	Based on paragraph 9.9		
	Rate of capacitance change	\pm 7.5% or \pm 0.75 pF , whichever is larger.	Test temperature : 40 ± 2°C Relative humidity : 90% to 95%		
	Dissipation factor (tanδ)	0.5% or less	Applied voltage : rated voltage Test time : 500 to 524 hrs.		
	Insulation resistance	500M Ω or 25M Ω ·μF , whichever is smaller	Capacitance measured after 24 ± 2 hrs.		
- High-	Appearance	There must be no mechanical damage.	- Based on paragraph 9.10		
	Rate of capacitance change	\pm 3.0% or \pm 0.3 pF , whichever is larger.	Test temperature : Max. operating temp.		
temperature load test	Dissipation factor (tanδ)	0.3% or less	Applied voltage : rated voltage × 200% Test time : 1,000 to 1,048 hrs.		
.553 1001	Insulation resistance	1,000M Ω or 50M Ω ·μF , whichever is smaller	Capacitance measured after 24 ± 2		

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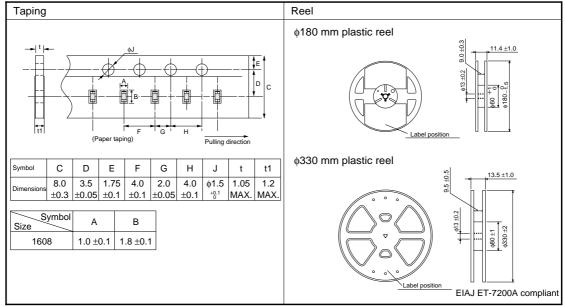
Class 2 (High dielectric constant)

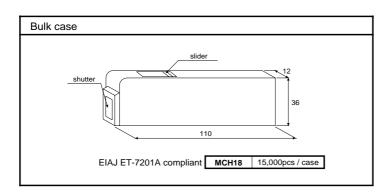
	lectric constant)				
Temperature characteristics		CN (R) (B) (X7R)	FN (F) (Y5V)	Test methods/conditions (based on JIS C 5102)	
Operating temperature		-55°C ~ +125°C	-30°C ~ +85°C		
Nominal capacitance (C)		Must be within the specified tolerance range.		Based on paragraph 7.8 Measured at room temperature and standard humidity	
Dissipation facto	r (tanδ)	2.5% or less 5.0% or less (when rated voltage is 16V: 3.5% or less) (when rated voltage is 16V: 7.5% or less)		Measurement frequency: 1 ± 0.1 kHz	
Insulation resistance (IR)		10,000 MΩ or 500 MΩ ·	μF, whichever is smaller	Based on paragraph 7.6 Measurement is made after rated voltage is applied for $60 \pm 5s$.	
Withstanding voltage		The insulation mus	st not be damaged.	Based on paragraph 7.1 Apply 250% of the rated voltage for 1 to 5s then mean	
Temperature ch	naracteristics	Within ± 15%	+ 22, + 82%	The temperature coefficients in paragraph 7.12, table 8, condition B, are based on measurements carried out at 20°C, with no voltage applied.	
Terminal adherence		No detachment or s	signs of detachment	Based on paragraph 8. 11. 2. Apply 5N for 10 ± 1s in the direction indicated by the arrow.	
	Appearance	There must be no mechanical damage.		Chip is mounted to a board in the	
Resistance to vibration	Rate of capacitance change	Must be within i	manner shown on the right, subjected to vibration (type A in paragraph 8.2), and measured 48 ± 4 hrs. later.		
	Dissipation factor ($tan\delta$)	Must satisfy initia			
Solderability		At least 3/4 of the surface of the two terr	minals must be covered with new solder.	Based on paragraph 8. 13 Soldering temperature: $235 \pm 5^{\circ}$ C Soldering time : 2 ± 0.5 s	
	Appearance	There must be no mechanical damage.			
	Rate of capacitance change	e Within ± 5.0% Within ± 20.0% Must satisfy initial specified value.		Based on paragraph 8. 14. Soldering temperature: 260 ± 5°C	
Resistance to soldering	Dissipation factor (tanδ)				
heat	Insulation resistance	10,000MΩ or 500MΩ · μF, whichever is smaller		Soldering time $: 5 \pm 0.5s$ Preheating $: 5 \pm 0.5s$ $: 150 \pm 10^{\circ}\text{C}$ for 1 to 2 min.	
	Withstanding voltage	The insulation mus			
	Appearance	There must be no n			
Temperature	Rate of capacitance change	Within ± 7.5%	Within ± 20.0%	Based on paragraph 9.3 Number of cycles : 5	
cycling	Dissipation factor (tanδ)	Must satisfy initial specified value.		Capacitance measured after 48 ± 4 hrs	
	Insulation resistance	10,000MΩ or 500MΩ · μ			
Humidity load test	Appearance	There must be no n	nechanical damage.	Based on paragraph 9.9	
	Rate of capacitance change	± 12.5% or less	Within ± 30.0%	Test temperature: 40 ± 2°C	
	Dissipation factor (tanδ)	5.0% or less	7.5% or less (when rated voltage is 16V: 10.0%)	Relative humidity: 90% to 95% Applied voltage : rated voltage Test time : 500 to 524 hrs.	
	Insulation resistance	500M Ω or 25M Ω · μF, whichever is smaller		Capacitance measured after 48 \pm 4 hrs	
	Appearance	There must be no mechanical damage.			
	Rate of capacitance change	Within ± 10.0%	Within ± 30.0%	Based on paragraph 9.10	
High- temperature load test	Dissipation factor ($tan\delta$)	5.0% or less	7.5% or less (when rated voltage is 16V: 10.0%)	Test temperature: Max. operating temp Applied voltage : rated voltage × 200% Test time : 1,000 to 1,048 hrs.	
	Insulation resistance	1,000MΩ or 50MΩ · μl	F, whichever is smaller	Capacitance measured after 48 ± 4 hrs	

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Packaging specifications

(Units : mm)





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Electrical characteristics

■ A (C0G) Characteristics

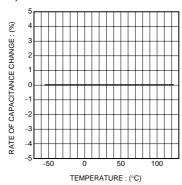


Fig.1 Capacitance - temperature characteristics

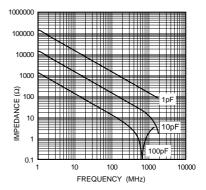


Fig.2 Impedance - frequency characteristics

■CN (X7R) Characteristics

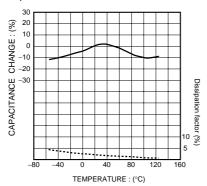


Fig.3 Capacitance - temperature characteristics

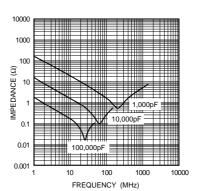


Fig.4 Impedance - frequency characteristics

■FN (Y5V) Characteristics

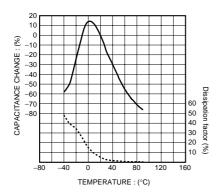


Fig.5 Capacitance - temperature characteristics

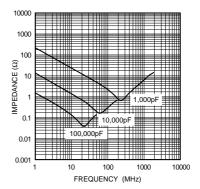
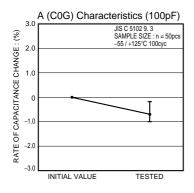
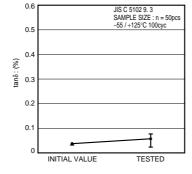


Fig.6 Impedance - frequency characteristics

^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

■ Temperature cycling test





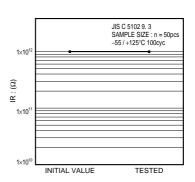
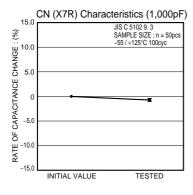
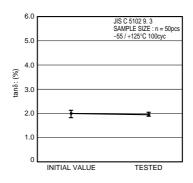


Fig.7 Rate of capacitance change

Fig.8 tanδ

Fig.9 Insulation resistance





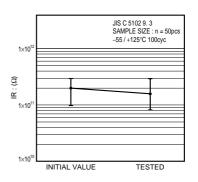
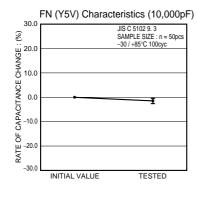
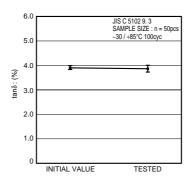


Fig.10 Rate of capacitance change

Fig.11 $tan\delta$

Fig.12 Insulation resistance





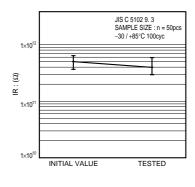


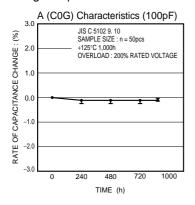
Fig.13 Rate of capacitance change

Fig.14 $tan\delta$

Fig.15 Insulation resistance

^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

■ High-temperature load test





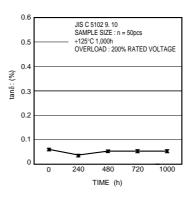


Fig.17 tanδ

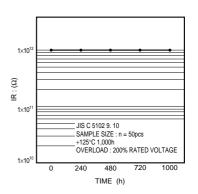


Fig.18 Insulation resistance

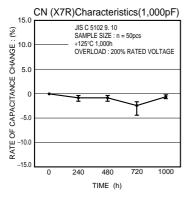


Fig.19 Rate of capacitance change

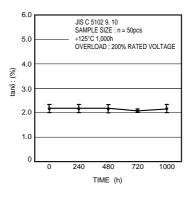


Fig.20 $\tan \delta$

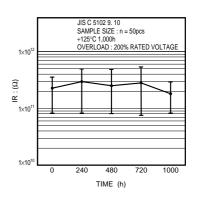


Fig.21 Insulation resistance

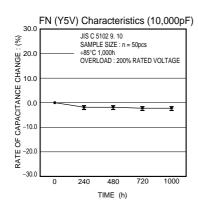


Fig.22 Rate of capacitance change

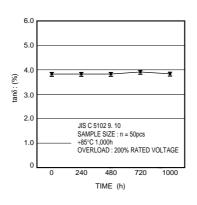


Fig.23 $tan\delta$

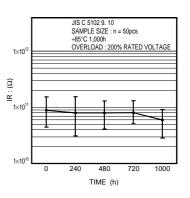
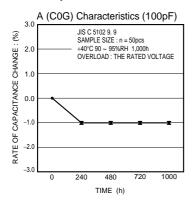
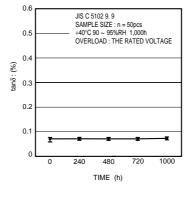


Fig.24 Insulation resistance

^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.

■ Humidity load test





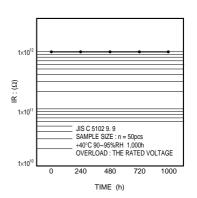
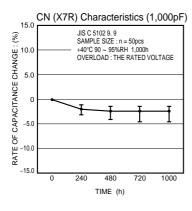
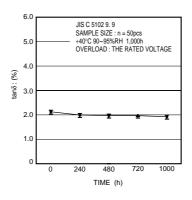


Fig.25 Rate of capacitance change

Fig.26 $tan \delta$

Fig.27 Insulation resistance





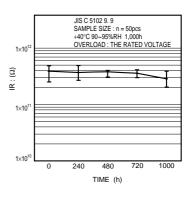
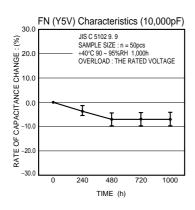
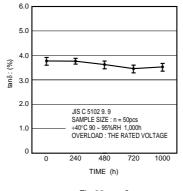


Fig.28 Rate of capacitance change

Fig.29 $tan\delta$

Fig.30 Insulation resistance





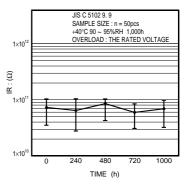


Fig.31 Rate of capacitance change

Fig.32 tanδ

Fig.33 Insulation resistance

^{*}The design and specifications are subject to change without prior notice. Before ordering or using, please check the latest technical specification.